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1. DMEA15B-001: Optimized Scintillator for High Resolution X-ray Imaging at 9keV

Release Date: 04-24-2015Open Date: 05-26-2015Due Date: 06-24-2015Close Date: 06-24-2015

Rapid Integrated Circuit (IC) inspection using x-ray microscopy requires novel x-ray scintillating materials with high efficiency and high spatial resolution. Current scintillator materials, such as Cesium Iodide (CsI), suffer from a trade-off between efficiency and spatial resolution. Novel materials with higher stopping power and light yields are necessary to address the stringent requirements o ...

STTR Defense Microelectronics ActivityDepartment of Defense

2. 9.01: Advanced Manufacturing

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

Advanced Manufacturing is “a family of activities that (a) depend on the use and coordination of information, automation, computation, software, sensing, and networking, and/or (b) make use of cutting edge materials and emerging capabilities enabled by the physical and biological sciences, for example nanotechnology, chemistry, and biology. This involves both new ways to manufacture existing pro ...

SBIR National Institute of Standards and TechnologyDepartment of Commerce

3. 9.01.01.73-R: Category-Theoretic Tools to Support Manufacturing Information Integration

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

This subtopic is calling for a software tool to test the categorical formalism on integration problems in smart manufacturing and additive manufacturing. Category theory has been identified as a flexible and straightforward mathematical formalism for establishing compatibility of information structures and setting up the required information exchange. The software tool must enable the creati ...

SBIR Department of Commerce

4. 9.01.02.73-R: Computer Aided Standards Development (CASD) – A Software Tool to Automate the Standards Development Process

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

The development of documentary and test standards is a long and tedious process. Challenges facing standards developers include complex, inadequately defined terminology, and rapidly changing associated information content. Even after a standard is “set,” its implementation and adoption can be hampered by the gap between the technical requirements of that standard and the technol ...

SBIR Department of Commerce

5. 9.01.03.68-R: High-Throughput Manufacturing Methods for Engineered MRI Contrast Agents

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

Microfabricated magnetic imaging agents with greater sensitivity and new functionality for magnetic resonance imaging (MRI) have recently been demonstrated at NIST [1-4]. The technology relies on thin-film fabrication methods adapted from the semiconductor industry. This “top-down” approach is expensive and suffers from low yield compared to “bottom-up” methods based ...

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6. 9.01.04.68-R: Laser Power Meter for Manufacturing Applications

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

The decreasing cost and increasing efficiency of high-power lasers is revolutionizing manufacturing in the U.S. and around the world. Multi-kilowatt lasers are now routinely used for welding, cutting, and additive manufacturing. Precision control of these processes, and thus the uniform quality of the manufactured product, requires a meter that can measure the power of such lasers with an uncertai ...

SBIR Department of Commerce

7. 9.01.05.68-R: Optical Microscopy as Applied to Fabrication of Atomic-Scale Devices

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

NIST seeks development of an optical imaging system that has micrometer resolution, an image field of 50 to 200 micrometers, and a depth of focus that ensures image quality over the field of view of interest. Such a system must have a working distance of nominally 20 cm, image an object that is in vacuum, and potentially have flexibility to work around obstructed sight paths. To set the context, ...

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8. 9.01.06.73-R: Predictive Modeling Tools for Metal-Based Additive Manufacturing

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

NIST seeks the development of tools that rely on a suite of physics-based and empirical models to support predictive analyses of metal-based additive manufacturing (AM) processes and products. Physics-based models will be developed in such a way to ensure reusability in a predictive environment, irrespective of product geometry. The tool will support reliable and repeatable microstruct ...

SBIR Department of Commerce

9. 9.01.07.63-R: Stroboscopic Method for Dynamic Imaging in a Transmission Electron Microscope at GHz Frequencies

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

A large portion of the global information technology (IT) infrastructure relies on nanoscale devices operating between 1 and 5 GHz. Familiar examples are GPS (1.5 GHz), cellular and wireless communication (2.4 GHz), dynamic random access memory (DRAM, 2 GHz) and computer processors (3 GHz). Although of wide-interest and the subject of many research and development efforts, the capability of ...

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10. 9.01.08.61-R: Tuning Germanium Crystal Reflectivity and Mosaic

Release Date: 03-09-2015Open Date: 03-09-2015Due Date: 05-15-2015Close Date: 05-15-2015

The standard for performance in monochromatic scattering of neutrons and x-rays has been pyrolytic graphite crystals (PG). PG has the disadvantages of scattering higher order wavelengths and it has only two useful reflections (002 and 004) that limit flexibility in

desired wavelength and resolution. If the properties of germanium crystals could be tuned so that the reflectivity performance i ...

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